Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs

 Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent $J-\overline{K}$ positive-edge-triggered flip-flops. A low level at the preset or clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and \overline{K} inputs meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and \overline{K} inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by grounding \overline{K} and tying J high. They also can perform as D-type flip-flops if J and \overline{K} are tied together.

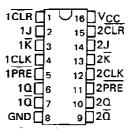
The SN54109 and SN54LS109A are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74109 and SN74LS109A are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)

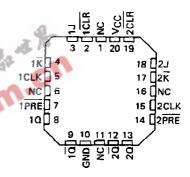
-	INI	PUTS	\		OUT	PUTS
PRE	CLR	CLK	J	K	Q	Q
T	H	X	Х	Х	H	L
Н	L	×	X	Х	L	н
L	L	X	Х	Х	нţ	Нţ
н	н	t	L	L	L	н
H	Н	t	Н	L	TOG	3LE
н	н	Ť	Ł	н	O _D	₫₀
Н	н	Ť	Н	н	н	L
LH.	H	L	×	Х	_00	

 $^{^\}dagger$ The output levels in this configuration are not guaranteed to meet the minimum levels for VOH if the lows at preset and clear are near V1L maximum. Furthermore, this configuration is nonstable; that is, it will not persist when preset or clear return to their inactive (high) level.

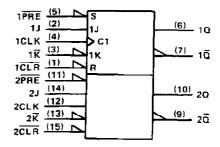
SN54109, SN54LS109A...J OR W PACKAGE SN74109...N PACKAGE SN74LS109A...D OR N PACKAGE (TOP VIEW)



SN54LS109A . . . FK PACKAGE (TOP VIEW)



logic symbol‡

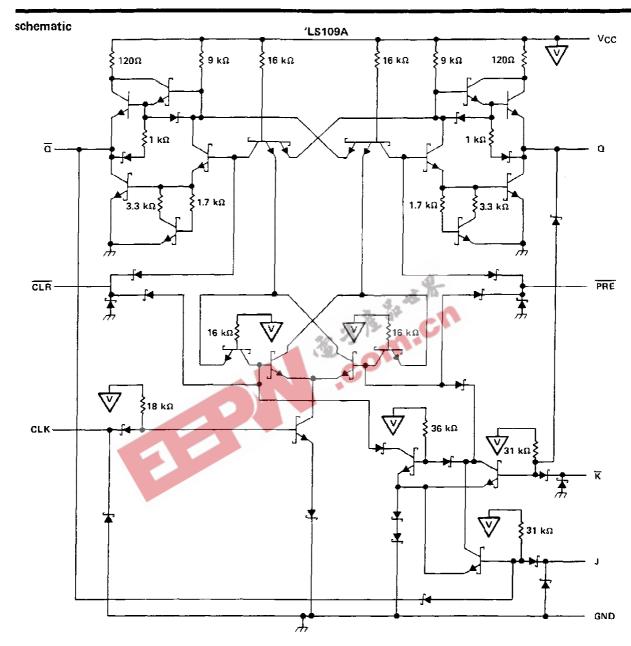


[‡]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN54109, SN74109 DUAL J.K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

logic diagram (positive logic) 109 PRE -CLK- $\overline{\mathbf{K}}$ CLR schematics of inputs and outputs · ′109 EQUIVALENT OF EACH INPUT TYPICAL OF ALL OUTPUTS Vcc-130 Ω NOM R_{eq} INPUT OUTPUT I_{IL} MAX – 1.6 mA H_{eq} NOM 4 kΩ - 3.2 mA $2\,k\Omega$ 1.3 kΩ -4.8 mA



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)		7 V
Input voltage: '109		5.5 V
Operating free-air temperature range:	SN54'	- 55°C to 125°C
	SN74'	0°C to 70°C
Storage temperature range		65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



SN54109, SN74109 DUAL J.K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

				SN54109			SN74109		
			MIN	MOM	MAX	MIN	NOM	MAX	UNIT
۷ <u>c</u> c	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
ViH	High-level input voltage		2	 •		2			V
VΙL	Low-level input voltage				8.0			0.8	V
ІОН	High-level output current				- 0.8			- 0.8	mA
10L	Low-level output current				16			16	mA
	Pulse duration	CLK high ar low	20			20			
t _w	- Luise dui ation	PRE or CLR low	20	•		20			ns
t _{su}	Input setup time before CLK 1		10			10			ns
t _{h_}	Input hold time-data after CLK1		6			6			ns
TΑ	Operating free-air temperature		55		125	Q		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†		SN54109			SN74109		
-			TYP# N	IAX	MIN	TYP	MAX	TINU
Vικ	V _{CC} = MIN, = - 12 mA	_ 1	-	1.5			- 1.5	V
V _{OH}	$V_{CC} = MIN$, $V_{IH} = 2 V$, $V_{IL} = 0.8 V$, $I_{OH} = -0.8 \text{ mA}$	2.4	3,4		2.4	3.4		٧
v _{OL}	$V_{CC} = MIN$, $V_{1H} = 2 V$, $V_{1L} = 0.8 V$, $I_{OL} = 16 \text{ mA}$	1	0.2	0.4		0.2	0.4	v
Ъ_	V _{CC} = MAX, V _I = 5.5 V	11.	_	1			1	mA
Jor K CLR				40 160			40 160	
PRE or CLK	V _{CC} = MAX, V _j ≈ 2.4 V			80			80	μА
J or K				1.6			- 1.6	
CERT SEE	$V_{CC} = MAX$, $V_{\parallel} = 0.4 \text{ V}$			4.8			4.8	mΑ
PRE¶	.00			3.2			- 3.2	
CLK				3.2			-3.2	
'os§	V _{CC} = MAX	– 30		85	30		- 85	mA
Icc#	VCC = MAX, See Note 2		9	15		9	15	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: With all outputs open, ICC is measured with the Q and Q outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, VCC = 5 V, TA = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS			TYP	MAX	UNIT	
f _{max}					25	33		MHz	
tPLH .	PRE	Q.				10	15	nş	
₹₽HL		ā				23	35	ns	
^t PLH	CLR	ত	$R_L = 400 \Omega$.	CL = 15 pF		10	15	ns	
tPHL	CEN		۵				17	25	ns
₹PLH	CLK	QorQ				10	16	ns	
^t PHL	CER	2012	_			18	28	ns	

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

⁵ Not more than one output should be shorted at a time.

Clear is tested with preset high and preset is tested with clear high.

[#] Average per flip flop.

SN54LS109A, SN74LS109A DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

			SN54LS109A			S	ÚNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
VIH	High-level input voitage		2			2			~
VIL	Low-level input voltage				0.7			0.8	V
ГОН	High-level output current				- 0,4		•	- 0.4	mA
TOL	Low-level output current				4			8	mA
fclock	Clock frequency		0		25	0		25	MHz
_	Dulan dunadina	CLK high	25			25			
tw	Pulse duration	PRE or CLR low	25			25			กร
	Constitution Cl KA	High-level data	35			35		_	
t _{su}	Setup time before CLK t Low-level data		25			25			ns
th	Hold time-data after CLK↑		5			5			ns
TA	Operating free-air temperature		- 55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		SN54LS109A		SN74LS109A			UNIT			
FARA	AMETER	'	EST COMPITIO	149.	MIN	TYP#	MAX	MIN	TYP‡	MAX	וואטן	
VIK		VCC = MIN,	I _I = - 18 mA	25.	7.3.	d	1.5		_	_ 1.5	V	
Vон		V _{CC} = MIN, I _{OH} = - 0.4 mA	V _{IH} = 2 V,	V _{IL} = MAX,	2.5	3.4		2.7	3.4	_	٧	
Va		V _{CC} = MIN, I _{OL} = 4 mA	VIL = MAX,	V _{IH} ≠ 2 V,	Le.	0.25	0,4		0.25	0.4	4 V	
VOL		V _{CC} = MIN, I _{OL} = 8 mA	VIL = MAX,	V _{1H} = 2 V,			-		0.35	0.5		
1. L	J, K or CLK	Vcc = MAX,	V ₁ = 7 V				0.1			0.1		
11	CLR or PRE	400 - MISA,	V - 7 V				0.2			0.2	mA	
	J, R or CLK	V _{CC} = MAX,	V ₁ = 2.7 V		<u></u>		20			20		
IH	CLR or PRE	VCC - MAA.	V = 2,7 V				40			40	μА	
	J, K or CLK	VCC = MAX,	V _I = 0.4 V				- 0.4			- 0.4	^	
11L -7	CLR or PRE	ACC - MIMY'	V - 0.4 V				- 0.8			- 0.8	mA	
os§		VCC = MAX.	See Note 4		- 20	_	 100	- 20		- 100	mA	
ICC (Tot	tai)	V _{CC} = MAX,	See Note 2			4	8		4	8	mA	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}				25	33		MHz
t _{PLH}	CLR, PRE	Q or Q	$R_L = 2 k\Omega$, $C_L = 15 pF$		13	25	ns
[†] PHL	or CLK				25	40	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at $V_{CC} = 5$ V, $T_{A} = 25^{\circ}$ C. §Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, ICC is measured with the Q and Q outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the 54 family and the 74 family, respectively with the minimum and maximum limits reduced to one half of their stated values.

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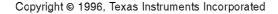
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